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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

	09/602,395
Application Serial No Filing Date	June 22, 2000
Filing Date	John T. Moore
Inventor	
Group Art Unit	
Examiner	MI22-1384
Attorney's Docket No. Title Methods of Forming Oxide Regions Over Semiconduc	tor Substrates

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed after the filing of the Request for Continued Examination (RCE) Application and before receipt of the first Office Action. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. §1.17(p) to Deposit Account No. 23-0925. Please credit Deposit Account No. 23-0925 with any overpayment of the above fee. **FAX RECEIVED**

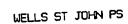
Citation of these references is respectfully requested.

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Respectfully submitted,

Date: 1-15-2002





IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

	09/602,395
Patent Application Serial No	
Filing Date	John T. Moore
Inventor	Micron Technology, Inc.
Assignee	2813
Group Art Unit	T, Pham
Examiner	MI22-1384
Attorney Docket No. Title: Methods of Forming Oxide Regi	ions Over Semiconductor Substrates

Assistant Commissioner for Patents Washington, D.C. 20231

CERTIFICATE OF FACSIMILE TRANSMISSION UNDER 37 CFR 1.8

I hereby certify that the following papers are being facsimile transmitted to the Patent and Trademark Office at (703) 872-9318 on the date shown below:

Supplemental Information Disclosure Statement w/PTO-1449 and 1. copy of cited reference

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788	AD	5,449,631	09-1995	Giewont et al.							
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